## Notice of References Cited Application/Control No. 10/696,077 Examiner Kristin D. Sandoval Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,816,948	11-2004	Kitamura et al.	711/152
*	В	US-7,124,436	10-2006	Okaue et al.	726/7
	O	US-			
	۵	US-			
	Ш	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	L	US-		·	
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0				•	
	Р					
	σ					
	R				,	***
	S					,
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	8							
	×							

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.